



FOR IMMEDIATE RELEASE

Contacts:

Aehr Test Systems

Greg Perkins

V.P. Worldwide Sales and Service

(510) 623-9400 x241

Financial Relations Board:

Erin Cox

Analyst/Investor Contact

(310) 854-8319

**AEHR TEST SYSTEMS RECEIVES FOX-1™ ORDERS
FROM A LEADING IC MANUFACTURER**

Fremont, CA (September 26, 2006) – Aehr Test Systems (Nasdaq: AEHR), a leading supplier of semiconductor test and burn-in equipment, today announced it has received orders from a leading IC manufacturer totaling over \$4 million for its FOX-1 full wafer, single touchdown parallel test systems and full wafer contactors. The systems and contactors are scheduled to ship during the next six months.

The customer originally provided development funding for the FOX-1 project and worked closely with Aehr Test to qualify the system for high-volume manufacturing. The first FOX-1 system was shipped to this customer in mid-September. The follow-on orders included in today's announcement will provide production capacity for full-wafer test of the customer's advanced memory devices.

“We are pleased to continue our relationship with this leading memory manufacturer,” said Greg Perkins, vice president of worldwide sales and service at Aehr Test Systems. “We believe the FOX-1 systems will become a key part of their test strategy and be a significant contributor to reducing their overall test costs.”

The FOX-1 full wafer parallel test system, a member of the FOX family of full wafer contact systems, is designed to test an entire wafer of IC devices with a single touchdown or be utilized for short-duration burn-in and test. This innovative solution combines full wafer contact, massively parallel test and Design For Test (DFT) technologies. Other members of Aehr Test's FOX family of products are focused on long-duration full wafer burn-in and test of products such as automotive ICs, DRAMs and VCSELs (laser diodes).

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing DRAM, flash and other memory and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX, MTX and MAX systems, and the DiePak® carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn in and functionally test complex devices, such as digital signal processors,

microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's Web site at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the FOX-1 technology, acceptance by customers of the FOX-1 systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K and 10-Q reports and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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